

Form PTO-1449  
(Rev. 8-83)U.S. Department of Commerce  
Patent and Trademark Office

Attorney Docket No. 0756-1996

Serial No. 09/352,362

**INFORMATION DISCLOSURE STATEMENT**

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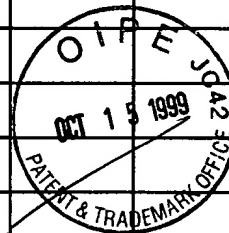
Applicant: Shunpei YAMAZAKI et al.

Filing Date: July 13, 1999

Group Art Unit: 2811

**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
<i>PD</i>	5,594,569	1/14/97	Konuma et al.			7/20/94
<i>PD</i>	5,643,826	7/1/97	Ohtani et al.			10/25/94
<i>PD</i>	5,923,962	7/13/99	Ohtani et al.			4/28/95

**FOREIGN PATENT DOCUMENTS**

Document Number	Date	Country	Class	Subclass	Translation Yes No
<i>PD</i> 7-130652	5/19/95	Japan			Abstract

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>PD</i>	"Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", Ryuichi Shimokawa et al., Japanese Journal of Applied Physics, Vol. 27, No. 5, pages 751-758, 1988.
<i>PD</i>	"Characteristics and Driving Scheme of Polymer-Stabilized Monostable FLCSD Exhibiting Fast Response Time and High Contrast Ratio with Gray-Scale Capability", H. Furue et al., SID 1998
<i>PD</i>	"A Full-Color Thresholdless Antiferroelectric LCD Exhibiting Wide Viewing Angle with Fast Response Time", T. Yoshida et al., SID DIGEST, pages 841-844, 1997.
<i>PD</i>	"Thresholds antiferroelectricity in liquid crystals and its application to displays", S. Inui et al., J. Mater. Chem., 6 (4), pages 671-673, 1996.

Examiner *PD*

Date Considered 11/06/01

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.